Analyzation of Sensor Data with the Aid of Deep Learning

Guest Editors:

Dr. József Sütő
1. Department of IT Systems and Networks, University of Debrecen, 4028 Debrecen, Hungary
2. Department of IT, Eszterházy Károly Catholic University, 3300 Eger, Hungary

Prof. Dr. Stefan Oniga
Department of Electric, Electronic and Computer Engineering, Technical University of Cluj-Napoca, Baia Mare 430122, Romania

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Message from the Guest Editors

Dear Colleagues,

The appearance of deep learning caused a great breakthrough in several research fields. The idea of using deep networks with new types of layers was very interesting to researchers because these techniques can automatically build high-level representations of the raw information.

The recent developments in hardware technology resulted in the lightweight deep models being hardware implementable on various embedded systems frameworks. Therefore, the data that come from sensors can be analyzed not just on the "server" side but also in the edge (or sensing) device.

The aim of this Special Issue is to encourage researchers to present original research results on the analyzation of sensor data with the aid of deep learning.

Dr. József Sütő
Prof. Dr. Stefan Oniga
Guest Editors

Special Issue

Editor-in-Chief

Prof. Dr. Vittorio M. N. Passaro
Dipartimento di Ingegneria Elettrica e dell'Informazione (Department of Electrical and Information Engineering), Politecnico di Bari, Via Edoardo Orabona n. 4, 70125 Bari, Italy

Message from the Editor-in-Chief

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